

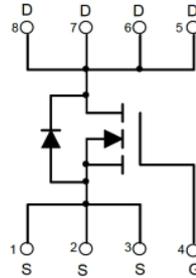
## Surface Mount N-Channel MOSFET

### Features

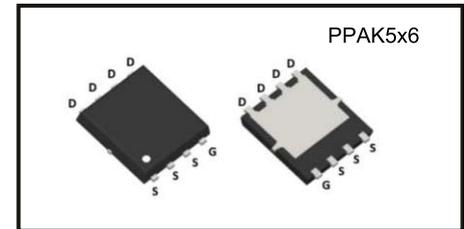
- Trench Power LV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low  $R_{DS(ON)}$

### Applications

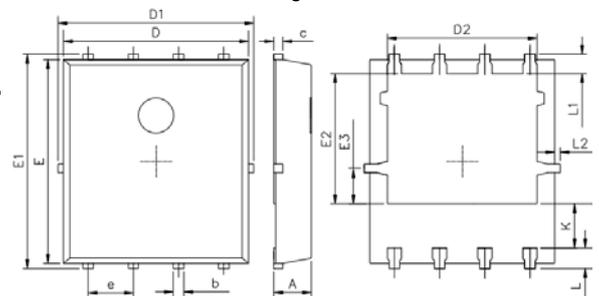
- High current load applications
- Load switching
- Hard switched and high frequency circuits
- Uninterruptible power supply



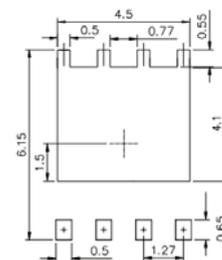
$V_{DS}$	60V
$I_D(@25^{\circ}\text{C})$	277A
$R_{DS(ON) \text{ max.}}$	1.1m $\Omega$



Package Dimensions



Recommended Land Pattern



UNIT:mm

DIM.	MIN	NOM	MAX
A	0.90	1.00	1.10
b	0.25	0.35	0.50
c	0.10	0.20	0.30
D	4.80	5.00	5.30
D1	4.90	5.10	5.50
D2	3.92	4.02	4.20
E	5.65	5.75	5.85
E1	5.90	6.05	6.20
E2	3.325	3.525	3.775
E3	0.80	0.90	1.00
e		1.27	
L	0.40	0.55	0.70
L1		0.65	
L2	0.00		0.15
K	1.00	1.30	1.50

### Absolute Maximum Ratings

( $T_c = 25^{\circ}\text{C}$  unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain Source Voltage	$V_{DS}$	60	V
Gate Source Voltage	$V_{GS}$	$\pm 20$	V
Drain Current Continuous	$I_D$	277 175	A
		@ $T_c = 25^{\circ}\text{C}$ @ $T_c = 100^{\circ}\text{C}$	
Drain Current Pulsed	$I_{DM}$	1109	A
Single Pulse Avalanche Energy	$E_{AS}$	1040	mJ
Power Dissipation	$P_D$	140	W
		@ $T_c = 25^{\circ}\text{C}$	
Storage Temperature Range	$T_{STG}$	-55 to +150	$^{\circ}\text{C}$
Operating Junction Temperature Range	$T_J$	-55 to +150	$^{\circ}\text{C}$
Thermal Resistance Junction to Case	$R_{\theta Jc}$	0.68	$^{\circ}\text{C/W}$
		Note1	

Notes:

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

**Electrical Characteristics @ T<sub>c</sub> =25°C (unless otherwise specified)**

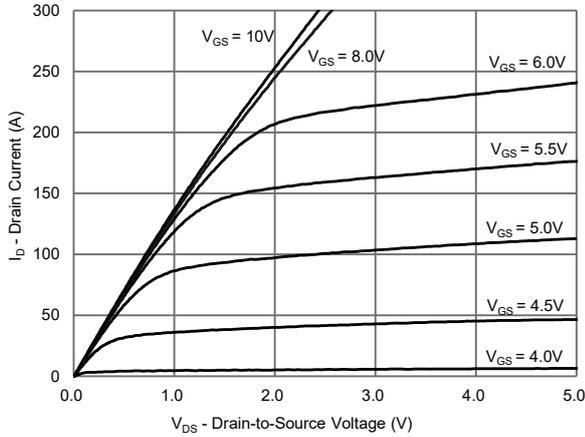
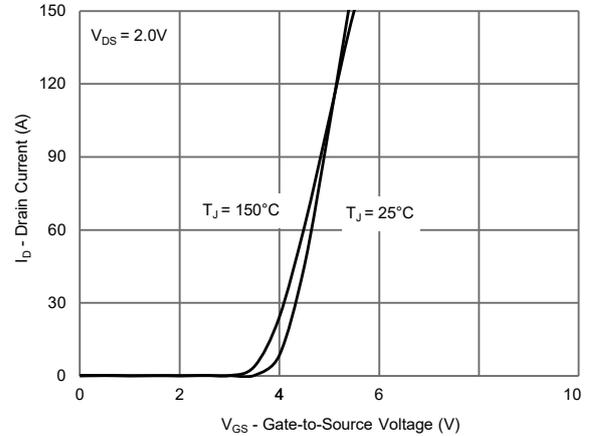
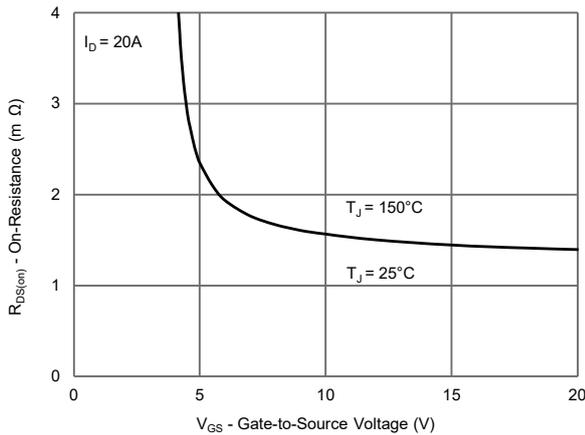
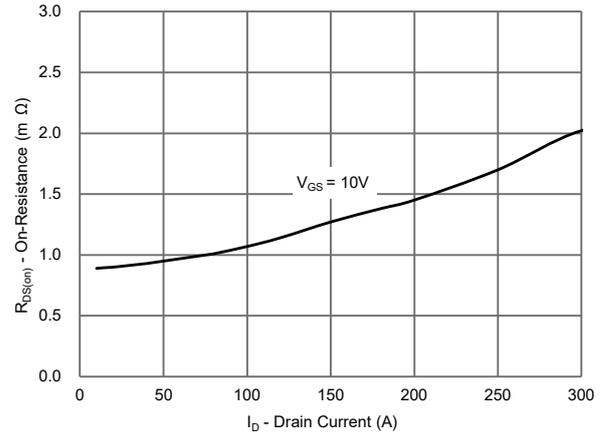
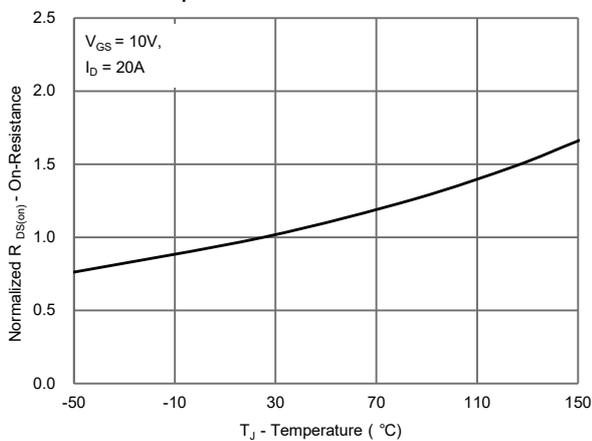
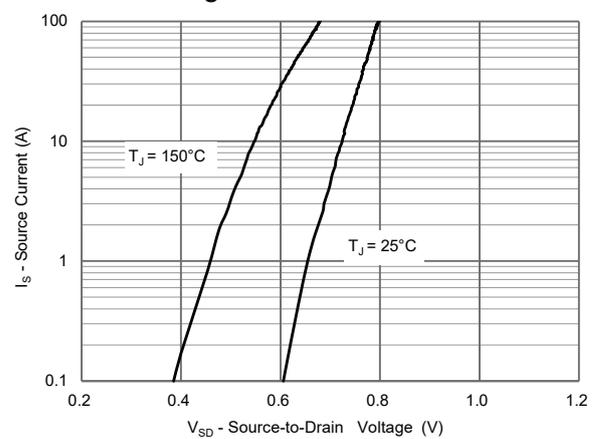
Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
<b>OFF Characteristics</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>DS</sub> =0.25mA	60	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =60V	-	-	1	μA
Gate To Source Forward Leakage	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
<b>ON Characteristics</b>						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =0.25mA	2.0	3.0	4.0	V
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	0.9	1.1	mΩ
Gate Resistance	R <sub>g</sub>	V <sub>DS</sub> =V <sub>GS</sub> =0V, f=1.0MHz	-	2.4	-	Ω
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> =5V, I <sub>D</sub> =20A	-	76	-	S
<b>Dynamic Characteristics</b> <small>Note2</small>						
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =30V V <sub>GS</sub> =0V Freq.=1.0MHz	-	7204	-	pF
Output Capacitance	C <sub>oss</sub>		-	3129	-	
Reverse Transfer Capacitance	C <sub>rss</sub>		-	202	-	
<b>Switching Characteristics</b> <small>Note2</small>						
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> =30V V <sub>GS</sub> =10V I <sub>D</sub> =20A R <sub>G</sub> =3.0Ω	-	28	-	ns
Rise Time	t <sub>r</sub>		-	45	-	
Turn-Off Delay Time	t <sub>d(off)</sub>		-	73	-	
Fall Time	t <sub>f</sub>		-	95	-	
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =30V V <sub>GS</sub> =10V I <sub>DS</sub> =20A	-	108	-	nC
Gate to Source Charge	Q <sub>gs</sub>		-	26	-	
Gate to Drain Charge	Q <sub>gd</sub>		-	24	-	
<b>Source-Drain Diode Characteristics</b>						
Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =2A	-	-	1.2	V
Body Continuous Source Current	I <sub>S</sub>	T <sub>C</sub> =25°C	-	-	277	A
Reverse Recovery Time	T <sub>rr</sub>	I <sub>S</sub> =20A, T <sub>J</sub> =25°C di/dt=100A/μs	-	73	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>		-	95	-	nC

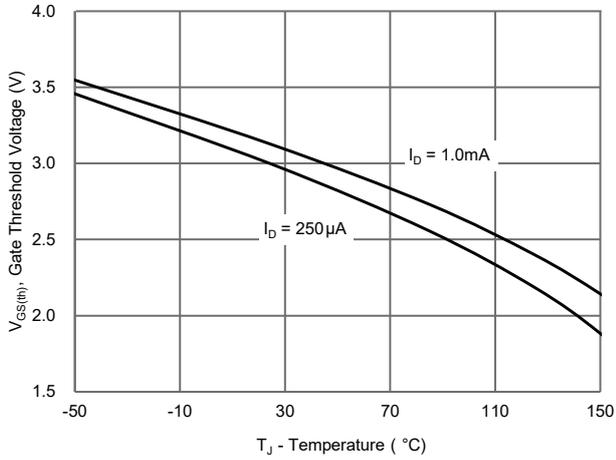
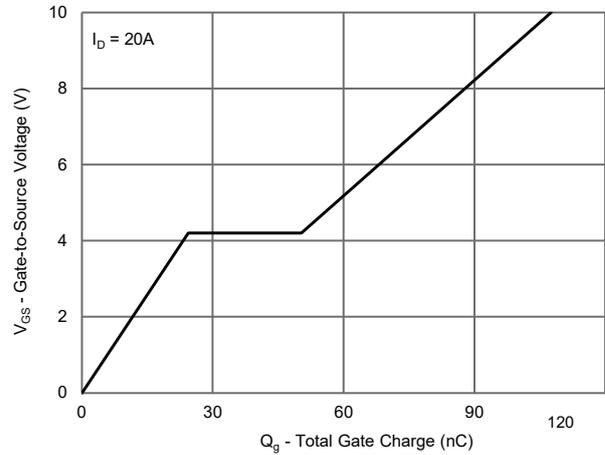
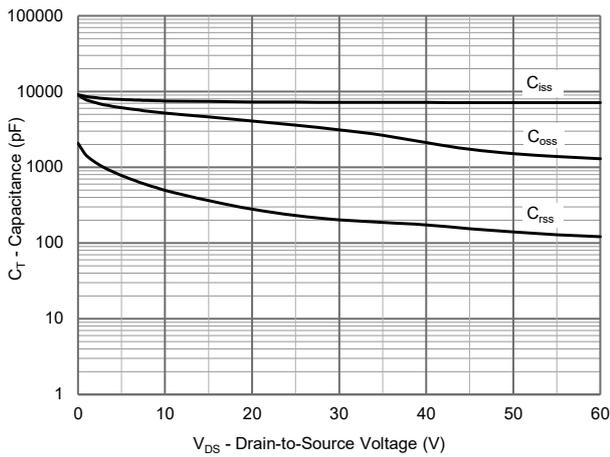
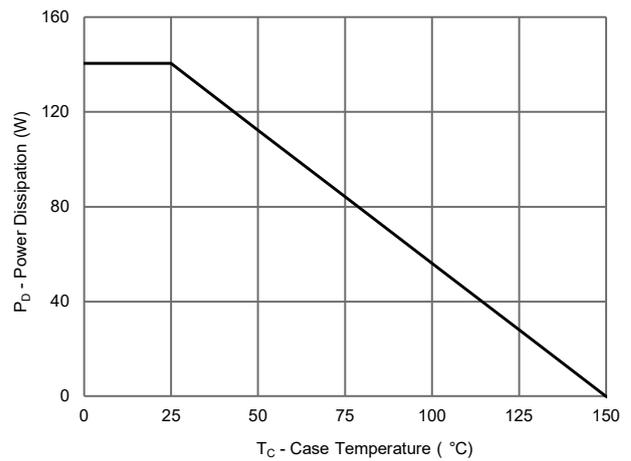
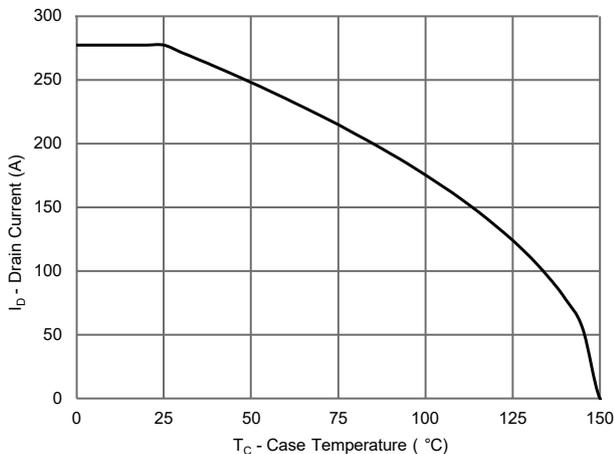
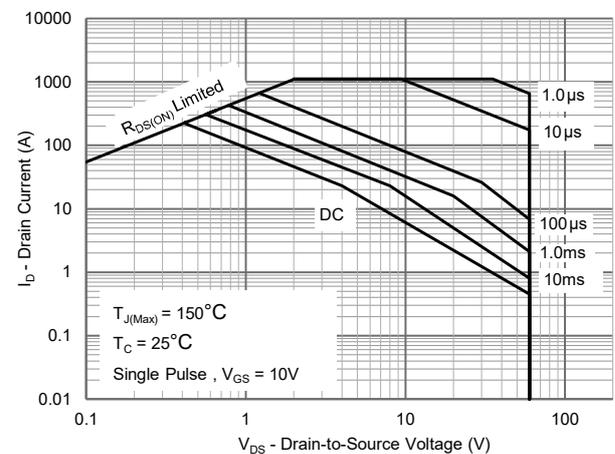
Notes:

2.The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%

3.EAS condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=30V, V<sub>G</sub>=10V, R<sub>G</sub>=25Ω, L=1mH.

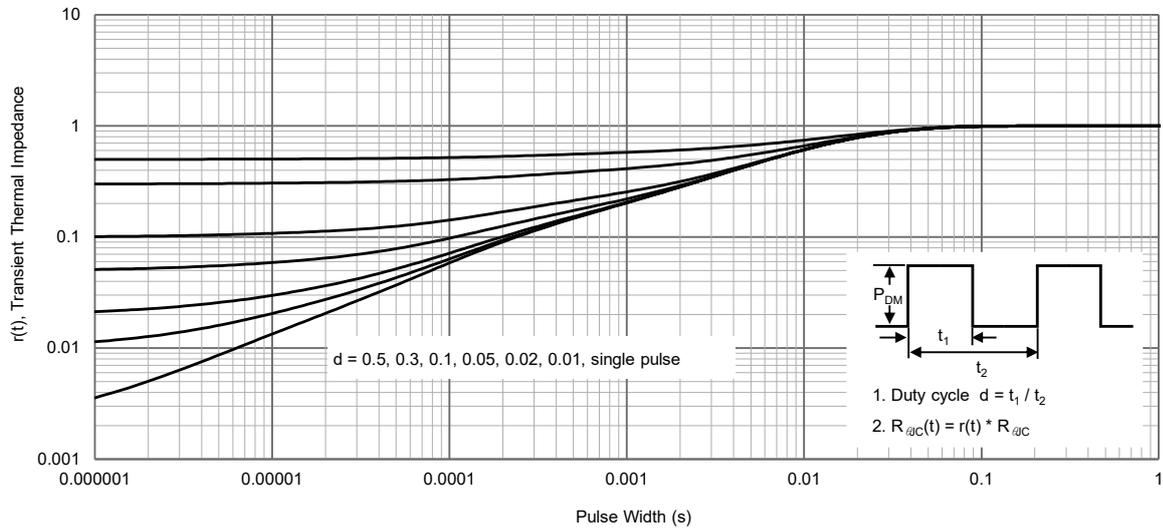
4.The power dissipation is limited by 150°C junction temperature

**Typical Performance Characteristics**
**Figure 1. Output Characteristics**

**Figure 2. Transfer Characteristics**

**Figure 3. On-Resistance vs. Gate-Source Voltage**

**Figure 4. On-Resistance vs. Gate-Source Voltage**

**Figure 5. On-Resistance vs. Junction Temperature**

**Figure 6. Source-Drain Diode Forward Voltage**


**Typical Performance Characteristics**
**Figure 7. Gate Threshold Variation vs. Junction Temperature**

**Figure 8. Gate Charge Characteristics**

**Figure 9. Capacitance Characteristics**

**Figure 10. Power Derating**

**Figure 11. Current Derating**

**Figure 12. Safe Operating Area**


**Typical Performance Characteristics**

Figure 13. Normalized Maximum Transient Thermal Impedance



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